_

Notice of References Cited

Application/Control No.

O9/449,679

Examiner

James M Hannett

Applicant(s)/Patent Under
Reexamination
SAKURAI ET AL.

Art Unit
Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification		
	Α	US-6,512,546 /	01-2003	Decker et al.	348/308		
	В	US-5,990,471 /	11-1999	Watanabe, Takashi	250/208.1		
	С	US-5,818,052 🗸	10-1998	Elabd, Hammam	250/370.09		
	D	US-2002/0154231 <	10-2002	Decker et al.	348/302		
	E	US-6,538,693 ×	03-2003	Kozuka, Hiraku	348/241		
	F	US-2001/0007471 /	07-2001	Beiley, Mark A.	348/241		
	G	US-6,587,146 /	07-2003	Guidash, Robert M.	348/308 /		
	Н	US-6,317,154 /	11-2001	Beiley, Mark A.	348/308		
	ı	US-6,243,134	06-2001	Beiley, Mark A.	348/308		
	J	US-6,133,862 /	10-2000	Dhuse et al.	341/118		
	к	US-6,011,251	01-2000	Dierickx et al.	250/208.1		
	L	US-5,172,249	12-1992	Hashimoto, Seiji	358/482		
	м	US-			1200		

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	Z					3,	
	0						
	Р						
	Q					,'	
	R						
	S						
	Т						

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U		·	,'
	V			
	w			
	х			,'

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.